

<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO.	APPLICATION NO.		
				<b>TROLOGY 02.02</b>		10/536,576	
				APPLICANT(S) <b>Szwaykowski et al.</b>			
				FILING DATE	GROUP ART UNIT		
<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
/HL/	4,583,855	04.22.1986	Bareket	356	351		
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/HL/	6,128,080	10/2000	Janik et al.				
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/HL/	2003/0095264	05/2003	Ruchet	356	491		
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
/HL/	DE 196 52 113	18.06.1998	Germany				
/HL/	WO 2004/051182	17.06.2004	PCT	G01B	9/02		
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/HL/		Hettwer, et al., "Three Channel Phase-Shifting Interferometer Using Polarization-Optics and a Diffraction Grating", The International Society for Optical Engineering, Optical Engineering, Vol. 39, pps. 960-966, April 2000 (abstract only).					
/HL/		Nakadate et al., "Real-Time Fringe Patter Processing and its Applications", Proc. of SPIE, Vol. 2544, pps. 74-86, June 1995 (abstract only).					
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<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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			Szwaykowski et al.				
			FILING February 6, 2006	GROUP ART			
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES      NO
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/HL/		Sivakumar, et al., "Large Surface Profile Measurement with Instantaneous Phase-Shifting Interferometry", Optical Engineering, February 2003, Vol. 42, Issue 2, pps. 367-372 (abstract only).					
/HL/		Koliopoulos, Chris L., "Simultaneous Phase-Shift Interferometer", Proceedings of SPIE, Vol. 1531, Advanced Optical Manufacturing and Testing II, 1992, pps. 119-127.					
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